

Program TXRF 2011

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- IL 1 TXRF-benchtop technology status, challenges and trends**
Ulrich Waldschläger
- IL 2 Green analytical chemistry strategies based on liquid-liquid micro-extraction for trace and speciation analysis by TXRF spectrometry**
E. Marguá, I. Queralt, C. Strelí, M. Hidalgo
- 3 Mt Kenya Soil Analysis: Application of TXRF and Laser Particle Size Analyzer**
M. J. Gatari, K. Shepherd, S. M. Gaita, J. Boman, S. Thorsson, A. Wagner
- 4 Trace metals in fine particles and bulk deposition sampled in Göteborg, Sweden**
Annemarie Wagner
- IL 5 Anion Species Analysis by Total Reflection X-Ray Fluorescence**
N. Kallithrakas-Kontos, V. Hatzistavros
- 6 Analysis of food samples by means of Total-Reflection X-Ray Fluorescence (TXRF) and Inductively-Coupled Plasma Mass Spectroscopy (ICP-MS): A comparative study**
Hagen Stosnach
- IL 7 Non-destructive species depth profiling of deeply buried nanostructures**
Beatrix Pollakowski
- 8 Influence of the excitation energy on absorption effects in TXRF analysis**
C. Horntrich, P. Kregsamer, S. Smolek, A. Maderitsch, P. Wobrauschek, R. Simon, A. Nutsch, C. Strelí
- IL 9 Characterization of ultra-shallow arsenic implants in silicon using grazing incidence and grazing exit x-ray spectroscopy**
F. Meirer, G. Pepponi, D. Ingerle, M.A. Sahiner, D. Giubertoni, E. Demenev, M.A. Foad, J.C. Woicik, A. Mehta, C Strelí, P. Pianetta
- 10 Complementary quantitative characterisations of buried nanolayers by conventional and grazing incidence X-ray spectrometry**
R. Unterumsberger, B. Pollakowski, M. Müller, B. Beckhoff
- 11 Micro-focused synchrotron radiation based high-resolution GEXRF applied to the depth profiling of low energy implants of P, In and Sb in Si and Ge**
Y. Kayser, D. Banaś, W. Cao, J.-Cl. Dousse, B. Fayard, P. Hönicke, J. Hoszowska, P. Jagodziński, A. Kubala-Kukuś, S. H. Nowak, M. Pajek, R. Unterumsberger
- 12 Grazing incidence X-ray fluorescence analysis of Pr doped Silicon Rich Silicon Oxide films**
G. Pepponi, M. Morales, K. R. Dey, F. Gourbilleau, D. Chateigner, M. Bersani, S. Pahlke
- IL13 Total Reflection X-Ray Fluorescence for Surface Analysis for Nanotechnologies**
Andreas Nutsch
- 14 TF for TXRF – Thin film technology applications or total reflection X-ray fluorescence analysis**
Markus Krämer, Reiner Dietsch, Thomas Holz, Danny Weißbach

- 15 Use of TXRF to monitor ultra-thin lanthanum oxide layers in complex high-k metal gate stacks for 32nm and 28nm technology nodes**
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- 16 Grazing incidence X-ray spectrometry for the characterization of nanoparticles deposited on flat surfaces**
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- IL 17 Low power TXRF**
Jun Kawai, Deh Ping TEE, Yasukazu Nakaye, Susumu Imashuku, Osami Wada
- 18 TXRF Spectrometer - Design with 50 W Mo tube and SDD**
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- 19 Grazing incidence X-ray absorption spectroscopy under non-ambient conditions: Recent developments at the DELTA storage ring**
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- IL 20 XRF imaging using total reflection in polycapillary optics and X-ray CCD detector**
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- IL21 Solid and Liquid Nanostructures characterized by X-ray Standing Waves**
M. Brücher, A. von Bohlen, R. Hergenröder
- 22 Grazing exit of X-ray secondary fluorescence at conditions of the planar waveguide-resonator application**
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- 23 Fast spatially resolved elemental distribution patterns for TXRF samples**
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P. Hoenicke, B. Beckhoff, D. Giubertoni, E. Demenev, Y. Kayser, J.A. van den Berg

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Improvement of calibration processes in TXRF of wafer surface analysis: Investigation of saturation effects in TXRF by comparing different sample shapes

C. Horntrich, P. Kregsamer, P. Wobrauschek, A. Nutsch, C. Strelt

Combined approach of GIXRF +XRR for Characterization of thin films on Si wafers

D. Ingerle, G. Pepponi, F. Meirer, C. Strelt, P. Wobrauschek, J. A. Van den Berg, M. A. Reading

Automatic optical alignment functions in TXRF instrument

Akihiko Iwata, Yuichiro Shimizu, Takashi Yamada

Fe speciation in ancient Attic pottery pigments: a non-destructive SR-XAS investigation
Fabrizio Bardelli, Germana Barone, Vincenza Crupi, Francesca Longo, Domenico Majolino, Paolo Mazzoleni, Valentina Venuti

Round robin test for TXRF and ToF-SIMS on various types of Ni samples on Si wafer surfaces within the network ANNA

P. Kregsamer, A. Nutsch, G. Borionetti, B. Beckhoff, M. Mueller, M. Polignano, G. Peponi, U. Fittschen, C. Strelt

Quantitative analysis of low concentration elements in a human biological substratum by total x-ray fluorescence spectrometer.

A. A. Kozhin, N. M. Novikovskii, G. O. Ponomarenko, V. M. Raznomazov, D. A. Sarichev, Y. I. Velichko

Gunshot residue investigations using TXRF

A. Wastl, B. Bogner, P. Kregsamer, P. Wobrauschek, C. Strelt

Paper Standards Database for Historical Documents Quantification

M. Manso, P. C. Chaves, A. Taborda, M. A. Reis, M. Becker, A. von Bohlen, J. Candeias, M. L. Carvalho

Investigation of TXRF Calibration with Picoliter Deposition Arrays

Chris Sparks, Ursula Fittschen, George Havrilla

Quantitative calculation of heavy metals and essential elements on commercial edible clams by x-ray spectrometry techniques and ICP-MS

E. Marguá, A. F. Marques, M. Hidalgo, I. Queralt, M. L. Carvalho

TXRF at ANKA Synchrotron

Rolf Simon

Sample preparation approaches for TXRF using three different pL pipette systems

Magnus Menzel, Ursula E. A. Fittschen, George J. Havrilla, Ulrich Waldschläger

Evaluation of the earth worm (*Eisenia fetida*) for the removal of uranium, lanthanum and cerium from a contaminated substrate and the effect on biological parameters

Lué Merú Marcó Parra, Alí Timaure, Lyzeth Abdala, Eduardo Greaves

Direct analysis of worm tissue using Total Reflection X-Ray Fluorescence

Lué-Merú Marcó Parra, Alí Timaure, Cristina Vázquez, Graciela Custo

TXRF: A Quality Assurance Procedure for Trace Elements in Tropical Soils

Jheanell James, Johan Boman

X-Ray Spectrometry as a Tool in Lithological Research: Studies of Till Samples

A. Kubala-Kukuś, M. Ludwikowska-Kędzia, D. Banaś, J. Braziewicz, U. Majewska, M. Pajek

Simulations of X-ray Transmission in Polycapillaries

P. Jagodziński, D. Banaś, A. Kubala-Kukuś, M. Pajek, J. Szlachetko, W. Cao, J.-Cl. Dousse, J. Hoszowska, Y. Kayser, S. Nowak

Investigations of speleothems by x-ray fluorescence microscopy using synchrotron radiation

P. Jagodziński, D. Banaś, W. Cao, J.-Cl. Dousse, J. Hoszowska, Y. Kayser, A. Kubala-Kukuś, S. Nowak, M. Pajek, M. Salome, J. Szlachetko

The use of Total Reflection X-ray Spectrometry (TXRF) in kinetic studies of mass limited samples: application to selenium adsorption in volcanic ashes

E. Margu, G. H. Floor, M. Hidalgo, G. Roman-Ross, C. Strel, P. Kregsamer, I. Queralt

Determination of platinum group metal catalyst residues in active pharmaceutical ingredients by means of Total Reflection X-ray Spectrometry (TXRF)

E. Margu, M. Hidalgo, I. Queralt

Enhancement of XRF intensity using total reflection in Au-coated capillary optics

Takashi Nakazawa, Kazuhiko Nakano, Kouichi Tsuji

Investigation of elemental composition and surface structure of solid thin films by TXRF

M. A. Bunin, Y. I. Velichko, A. P. Kovtun, N. M. Novikovskii, D. A. Sarichev, Y. A. Stoyko, V. O. Ponomarenko, V. M. Raznomazov

TXRF and GF-AAS methods for the determination of Fe, Cu and Zn in human cell samples

Zs. Polgri, N. Szoboszlai, Zs. Ajtony, P. Kregsamer, C. Strel, A. Rti, B. Budai, V. G. Mihucz, G. Zray

Analysis of Elements Concentration in Human Biological Material by Application TXRF Method

D. Bana, J. Braziewicz, A. Kubala-Kuku, U. Majewska, M. Pajek, J. Wudarczyk-Mocko, G. Antczak, B. Borkowska, S. Gzd

Study of chemically modified halloysite samples with X-ray fluorescence and X-ray powder diffraction methods

D. Bana, J. Braziewicz, A. Kubala-Kuku, U. Majewska, M. Pajek, K. Wilamowski, P. Somkiewicz, B. Szczepanik

A Comparison of X-Ray Fluorescence spectrometric techniques for the determination of phosphorus and iron in soils

Nijole Young, Johan Boman

Spectroscopic determination of the elemental composition of PM2.5 particles sampled in industrial and urban areas of Greater Cairo, Egypt

Johan Boman, Bernhard Welz, Ivan N.B. Castilho, Asmaa Magdy, S. K. Hassan, Abdallah A. Shaltout

Interface structure of Ti/Ni/Ti thin films studied by GI-XAFS and XRR

Xiangjun Wei, Haisheng Yu, Zheng Jiang, Shuo Zhang, Jiangqiang Wang, Yang Zou, Songqi Gu, Qian Gao, Yuying Huang

Sample preparation of seawater for TXRF analysis

T. Yoshioka, Y. Imanishi, K. Tsuji, Y. Shimizu, T. Yamada, H. Takabe, T. Doi, K. Akioka, M. Arai

Attenuation effects in TXRF

R. Padilla Alvarez

Heavy metals in urban soil of India investigated by TXRF and ICP

M. Rajak, N. K. Jaiswal, K. S. Patel, R. K. Patel, M. Lautent, P. Vannini, M. Bernardello, M. Salmistraro, C. Vischioni, L. Borgese, A. Gianoncelli, D. Cazzago, L. E. Depero, E. Bontempi

Geometrical Optics Modelling of Grazing Incidence X-ray Fluorescence of Nanoscaled Objects

S. H. Nowak, F. Reinhardt, H. Bresch, Y. Kayser, J. Osn, A. E. Pap